



CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board/AClass
500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

Evans Analytical Group, LLC
2710 Walsh Ave.
Santa Clara, CA 95051

has been assessed by AClass
and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the field(s) of

TESTING

Refer to the accompanying Scope(s) of Accreditation for information regarding the types of tests to which this accreditation applies.

ACT-1111

Certificate Number

AClass Approval

Certificate Valid: 08/12/2009-05/01/2011
Version No. 001



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated January 2009*).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

Evans Analytical Group, LLC.

2710 Walsh Ave., Santa Clara, CA 95051
 Sandeep Srivastava Phone: 408-496-4123

TESTING

Valid to: May 1, 2011

Certificate Number: ACT-1111

I. Electrical and Environmental Stress

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	DETECTION LIMIT/ RANGE/ EQUIPMENT
Voltage Stress	Integrated Circuits	Rise/Fall Time < 400 ps Voltage Accuracy +/- 15 %	JEDEC JESD22-A114 Electrostatic Discharge Sensitivity Test - Human Body Model MILSTD883 TM 3015.7 Electrostatic Discharge Sensitivity Classification	1024 Pin Capacity 100 V to 8 kV ThermoKeyTek Paragon
				768 Pin Capacity 100 V to 8 kV ThermoKeyTek MK2
			JEDEC JESD22-A115 Electrostatic Discharge Sensitivity Test - Machine Model	1024 Pin Capacity 50 V to 2 kV ThermoKeyTek Paragon
				768 Pin Capacity 50 V to 2 kV ThermoKeyTek MK2
			JEDEC JESD22-C101 Electrostatic Discharge Sensitivity Test - Field Induced Charged Device Model	50 V to 2 kV ThermoKeyTek RCDM
			ESDA STM 5.3.1 Electrostatic Discharge Sensitivity Test - Field Induced Charged Device Model	50 V to 2 kV ThermoKeyTek RCDM
			JEDEC JESD22A114 Electrostatic Discharge Human Body Model MILSTD883 TM 3015.7 Electrostatic Discharge Sensitivity Classification	2304 Pin Capacity 100 V to 8 kV Thermo Key Tek MK4



FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	DETECTION LIMIT/ RANGE/ EQUIPMENT
Voltage Stress	Integrated Circuits	Rise/Fall Time < 400 ps Voltage Accuracy +/- 15 %	JEDEC JESD22A115 Electrostatic Discharge Sensitivity Test - Machine Model	2304 Pin Capacity 50 V to 2 kV ThermoKey Tek MK4
Voltage Stress	Integrated Circuits	Rise/Fall Time < 400 ps Voltage Accuracy +/- 15 %	JEDEC Sensitivity Test - JESD78A Electrostatic Discharge Sensitivity Test – Latch Up	2304 Pin Capacity +/- 100 mA ThermoKey Tek MK4
Environmental Stress	Integrated Circuits	HTOL (High Temperature Operating Life)	MIL STD 883 Test Method 1005.8, 1006, 1015	85°~150°C 1-20 V/0-550 A DPBI (Dynamic Proposed Burn-In) A54SX32A-CQ84 RTAX250S-CQ208 RTAX2000S-CG624 RTAX2000S-CQ352
			Actel Procedure 2-04-00007, 2-04-00063, 2-04-00065, 2-04-00066	
		HTSL (High Temperature Storage Life)	JESD22-A103	(100~185) °C
		THB – Temperature Humidity Bias	JESD-A101	30 °C~85 °C (60~85) %RH Non-condensing
		PPOT – Pressure Pot	JESD22-A102	(121 to 135)°C, 20 PSI, 100 % Saturation
		HAST – Highly Accelerated Stress Test	JESD22-A110	110~145 °C, 35 PSI, 100 % Saturation 85 %RH (Max) Triotech 6000
		TMCL – Temperature Cycling	JESD22-A104 MIL STD 883 Test Method 1010 MIL STD 750 Test Method 1051	Condition A-N (Air to Air) (-55 to 125) °C 10 min dwell, Instantaneous Ramp; 5 min dwell 15 min Ramp
		Thermal Shock	MIL STD 883 TM 1011.9	(-73 to 166) °C (Liquid to Liquid)
		Moisture Resistance	MIL STD 883 TM 1004.7	-30 °C to 105 °C, 95 %RH (Max)



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Environmental Stress	Integrated Circuits	Seal	MIL STD 883 TM 1014.11	A1, A2, A4, C, C4 & C5 5 Torr for 30 min (75 to 80) PSI 4 hr He/FC Gross Leak: Bubble Test Fine Leak: 1.25×10^{-8} ATM cc/sec He
		Pre-conditioning	JESD22-A113-A	Level 1 ~6
		Salt Atmosphere	MIL STD 883 TM 1009.8	(20 000 to 50 000) mg/m ² per 24 hr
Final Test Program	Integrated Circuits	Ethernet	IEEE 802.3	93K Tester
		Wireless LAN	IEEE 802.11a/b/g/n	
		Broadband Wireless Access <WiMax </wiki/WiMax> Certification	IEEE 802.16	
		Mobile Broadband Wireless Access	IEEE 802.16e	
		Local Multipoint Distribution Service	IEEE 802.16.1	
		Radio Regulatory TAG	IEEE 802.18	
		Coexistence TAG	IEEE 802.19	
		Mobile Broadband Wireless Access	IEEE 802.20	
		Wireless Regional Area Network	IEEE 802.22	
		Nominal 3V/3.3 V Supply	JESD8C.01	
		Registered Buffer with Parity	JESD82-17	
		Radio Front End-Baseband (RF-BB Interface)	JESD96A	
		DDR2 SDRAM DIMM (FBDIMM)	JESD205	

Notes:

1. This scope is part of and must be included with the Certificate of Accreditation No. ACT-1111

Karl Greenway

Vice-President

